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### Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

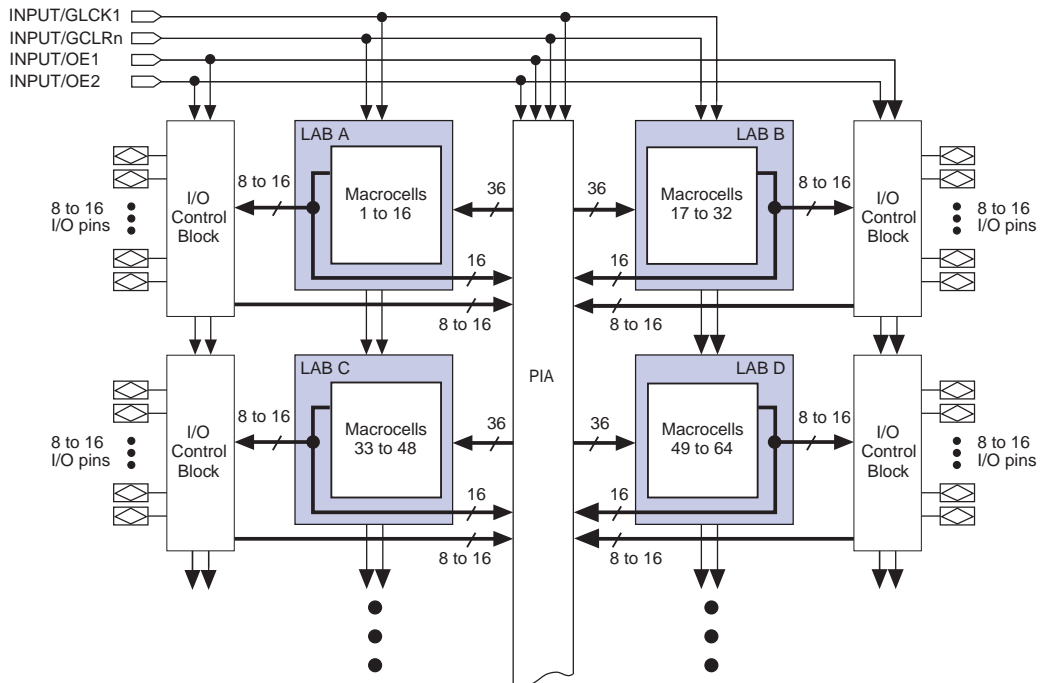
### Applications of Embedded - CPLDs

#### Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	4
Number of Macrocells	64
Number of Gates	1250
Number of I/O	36
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	44-TQFP
Supplier Device Package	44-TQFP (10x10)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/epm7064stc44-10f">https://www.e-xfl.com/product-detail/intel/epm7064stc44-10f</a>

The MAX 7000 architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. Figure 1 shows the architecture of EPM7032, EPM7064, and EPM7096 devices.

**Figure 1. EPM7032, EPM7064 & EPM7096 Device Block Diagram**



When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to  $V_{CC}$ , the output is enabled.

The MAX 7000 architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

## **In-System Programmability (ISP)**

MAX 7000S devices are in-system programmable via an industry-standard 4-pin Joint Test Action Group (JTAG) interface (IEEE Std. 1149.1-1990). ISP allows quick, efficient iterations during design development and debugging cycles. The MAX 7000S architecture internally generates the high programming voltage required to program EEPROM cells, allowing in-system programming with only a single 5.0 V power supply. During in-system programming, the I/O pins are tri-stated and pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k $\Omega$ .

ISP simplifies the manufacturing flow by allowing devices to be mounted on a printed circuit board with standard in-circuit test equipment before they are programmed. MAX 7000S devices can be programmed by downloading the information via in-circuit testers (ICT), embedded processors, or the Altera MasterBlaster, ByteBlasterMV, ByteBlaster, BitBlaster download cables. (The ByteBlaster cable is obsolete and is replaced by the ByteBlasterMV cable, which can program and configure 2.5-V, 3.3-V, and 5.0-V devices.) Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling and allows devices to be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. Because some in-circuit testers cannot support an adaptive algorithm, Altera offers devices tested with a constant algorithm. Devices tested to the constant algorithm have an "F" suffix in the ordering code.

The Jam™ Standard Test and Programming Language (STAPL) can be used to program MAX 7000S devices with in-circuit testers, PCs, or embedded processor.

By using an external 5.0-V pull-up resistor, output pins on MAX 7000S devices can be set to meet 5.0-V CMOS input voltages. When  $V_{CCIO}$  is 3.3 V, setting the open drain option will turn off the output pull-up transistor, allowing the external pull-up resistor to pull the output high enough to meet 5.0-V CMOS input voltages. When  $V_{CCIO}$  is 5.0 V, setting the output drain option is not necessary because the pull-up transistor will already turn off when the pin exceeds approximately 3.8 V, allowing the external pull-up resistor to pull the output high enough to meet 5.0-V CMOS input voltages.

### Slew-Rate Control

The output buffer for each MAX 7000E and MAX 7000S I/O pin has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay of 4 to 5 ns. In MAX 7000E devices, when the Turbo Bit is turned off, the slew rate is set for low noise performance. For MAX 7000S devices, each I/O pin has an individual EEPROM bit that controls the slew rate, allowing designers to specify the slew rate on a pin-by-pin basis.

## Programming with External Hardware

MAX 7000 devices can be programmed on Windows-based PCs with the Altera Logic Programmer card, the Master Programming Unit (MPU), and the appropriate device adapter. The MPU performs a continuity check to ensure adequate electrical contact between the adapter and the device.



For more information, see the [\*Altera Programming Hardware Data Sheet\*](#).

The Altera development system can use text- or waveform-format test vectors created with the Text Editor or Waveform Editor to test the programmed device. For added design verification, designers can perform functional testing to compare the functional behavior of a MAX 7000 device with the results of simulation. Moreover, Data I/O, BP Microsystems, and other programming hardware manufacturers also provide programming support for Altera devices.



For more information, see the [\*Programming Hardware Manufacturers\*](#).

## IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 7000 devices support JTAG BST circuitry as specified by IEEE Std. 1149.1-1990. [Table 9](#) describes the JTAG instructions supported by the MAX 7000 family. The pin-out tables (see the Altera web site (<http://www.altera.com>) or the *Altera Digital Library* for pin-out information) show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

**Table 9. MAX 7000 JTAG Instructions**

JTAG Instruction	Devices	Description
SAMPLE/PRELOAD	EPM7128S EPM7160S EPM7192S EPM7256S	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins.
EXTEST	EPM7128S EPM7160S EPM7192S EPM7256S	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation.
IDCODE	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
ISP Instructions	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	These instructions are used when programming MAX 7000S devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, BitBlaster download cable, or using a Jam File (.jam), Jam Byte-Code file (.jbc), or Serial Vector Format file (.svf) via an embedded processor or test equipment.

The instruction register length of MAX 7000S devices is 10 bits. Tables 10 and 11 show the boundary-scan register length and device IDCODE information for MAX 7000S devices.

**Table 10. MAX 7000S Boundary-Scan Register Length**

Device	Boundary-Scan Register Length
EPM7032S	1 (1)
EPM7064S	1 (1)
EPM7128S	288
EPM7160S	312
EPM7192S	360
EPM7256S	480

**Note:**

- (1) This device does not support JTAG boundary-scan testing. Selecting either the EXTEST or SAMPLE/PRELOAD instruction will select the one-bit bypass register.

**Table 11. 32-Bit MAX 7000 Device IDCODE** Note (1)

Device	IDCODE (32 Bits)				1 (1 Bit) (2)
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer's Identity (11 Bits)		
EPM7032S	0000	0111 0000 0011 0010	00001101110		1
EPM7064S	0000	0111 0000 0110 0100	00001101110		1
EPM7128S	0000	0111 0001 0010 1000	00001101110		1
EPM7160S	0000	0111 0001 0110 0000	00001101110		1
EPM7192S	0000	0111 0001 1001 0010	00001101110		1
EPM7256S	0000	0111 0010 0101 0110	00001101110		1

**Notes:**

- (1) The most significant bit (MSB) is on the left.  
 (2) The least significant bit (LSB) for all JTAG IDCODEs is 1.

## Design Security

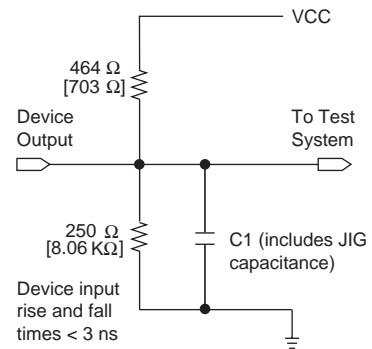
All MAX 7000 devices contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a proprietary design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is reprogrammed.

## Generic Testing

Each MAX 7000 device is functionally tested. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in [Figure 10](#). Test patterns can be used and then erased during early stages of the production flow.

**Figure 10. MAX 7000 AC Test Conditions**

*Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V devices and outputs. Numbers without brackets are for 3.3-V devices and outputs.*



## QFP Carrier & Development Socket

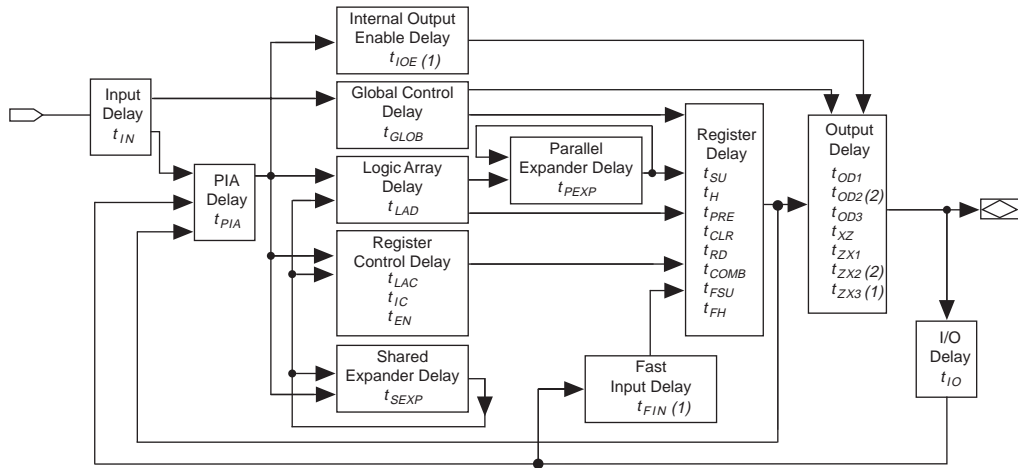
MAX 7000 and MAX 7000E devices in QFP packages with 100 or more pins are shipped in special plastic carriers to protect the QFP leads. The carrier is used with a prototype development socket and special programming hardware available from Altera. This carrier technology makes it possible to program, test, erase, and reprogram a device without exposing the leads to mechanical stress.



For detailed information and carrier dimensions, refer to the [QFP Carrier & Development Socket Data Sheet](#).



MAX 7000S devices are not shipped in carriers.

**Figure 12. MAX 7000 Timing Model****Notes:**

- (1) Only available in MAX 7000E and MAX 7000S devices.
- (2) Not available in 44-pin devices.

The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. Figure 13 shows the internal timing relationship of internal and external delay parameters.



For more information, see *Application Note 94 (Understanding MAX 7000 Timing)*.



**Table 21. MAX 7000 & MAX 7000E External Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			MAX 7000E (-10P)		MAX 7000 (-10) MAX 7000E (-10)		
			Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t <sub>SU</sub>	Global clock setup time		7.0		8.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.5		0.5		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		5.0		5	ns
t <sub>CH</sub>	Global clock high time		4.0		4.0		ns
t <sub>CL</sub>	Global clock low time		4.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time		2.0		3.0		ns
t <sub>AH</sub>	Array clock hold time		3.0		3.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		10.0		10.0	ns
t <sub>ACH</sub>	Array clock high time		4.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		4.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	4.0		4.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			10.0		10.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	100.0		100.0		MHz
t <sub>ACNT</sub>	Minimum array clock period			10.0		10.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	100.0		100.0		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	125.0		125.0		MHz

Table 25. MAX 7000 & MAX 7000E External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-15		-15T		-20		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>SU</sub>	Global clock setup time		11.0		11.0		12.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		–		5.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.0		–		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		8.0		8.0		12.0	ns
t <sub>CH</sub>	Global clock high time		5.0		6.0		6.0		ns
t <sub>CL</sub>	Global clock low time		5.0		6.0		6.0		ns
t <sub>ASU</sub>	Array clock setup time		4.0		4.0		5.0		ns
t <sub>AH</sub>	Array clock hold time		4.0		4.0		5.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>ACH</sub>	Array clock high time		6.0		6.5		8.0		ns
t <sub>ACL</sub>	Array clock low time		6.0		6.5		8.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	6.0		6.5		8.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			13.0		13.0		16.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	76.9		76.9		62.5		MHz
t <sub>ACNT</sub>	Minimum array clock period			13.0		13.0		16.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	76.9		76.9		62.5		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	100		83.3		83.3		MHz

**Table 26. MAX 7000 & MAX 7000E Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-15		-15T		-20		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			2.0		2.0		3.0	ns
$t_{IO}$	I/O input pad and buffer delay			2.0		2.0		3.0	ns
$t_{FIN}$	Fast input delay	(2)		2.0		—		4.0	ns
$t_{SEXP}$	Shared expander delay			8.0		10.0		9.0	ns
$t_{PEXP}$	Parallel expander delay			1.0		1.0		2.0	ns
$t_{LAD}$	Logic array delay			6.0		6.0		8.0	ns
$t_{LAC}$	Logic control array delay			6.0		6.0		8.0	ns
$t_{IOE}$	Internal output enable delay	(2)		3.0		—		4.0	ns
$t_{OD1}$	Output buffer and pad delay Slow slew rate = off $V_{CCIO} = 5.0\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
$t_{OD2}$	Output buffer and pad delay Slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$ (7)		5.0		—		6.0	ns
$t_{OD3}$	Output buffer and pad delay Slow slew rate = on $V_{CCIO} = 5.0\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$ (2)		8.0		—		9.0	ns
$t_{ZX1}$	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 5.0\text{ V}$	$C1 = 35\text{ pF}$		6.0		6.0		10.0	ns
$t_{ZX2}$	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$ (7)		7.0		—		11.0	ns
$t_{ZX3}$	Output buffer enable delay Slow slew rate = on $V_{CCIO} = 5.0\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$ (2)		10.0		—		14.0	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5\text{ pF}$		6.0		6.0		10.0	ns
$t_{SU}$	Register setup time		4.0		4.0		4.0		ns
$t_H$	Register hold time		4.0		4.0		5.0		ns
$t_{FSU}$	Register setup time of fast input	(2)	2.0		—		4.0		ns
$t_{FH}$	Register hold time of fast input	(2)	2.0		—		3.0		ns
$t_{RD}$	Register delay			1.0		1.0		1.0	ns
$t_{COMB}$	Combinatorial delay			1.0		1.0		1.0	ns
$t_{IC}$	Array clock delay			6.0		6.0		8.0	ns
$t_{EN}$	Register enable time			6.0		6.0		8.0	ns
$t_{GLOB}$	Global control delay			1.0		1.0		3.0	ns
$t_{PRE}$	Register preset time			4.0		4.0		4.0	ns
$t_{CLR}$	Register clear time			4.0		4.0		4.0	ns
$t_{PIA}$	PIA delay			2.0		2.0		3.0	ns
$t_{LPA}$	Low-power adder	(8)		13.0		15.0		15.0	ns

**Table 28. EPM7032S Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{PIA}$	PIA delay	(7)		1.1		1.1		1.4		1.0	ns
$t_{LPA}$	Low-power adder	(8)		12.0		10.0		10.0		11.0	ns

**Notes to tables:**

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The  $t_{LPA}$  parameter must be added to this minimum width if the clear or reset signal incorporates the  $t_{LAD}$  parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3\text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in the low-power mode.

Tables 29 and 30 show the EPM7064S AC operating conditions.

**Table 29. EPM7064S External Timing Parameters (Part 1 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
tPD1	Input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
tPD2	I/O input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
tSU	Global clock setup time		2.9		3.6		6.0		7.0		ns
tH	Global clock hold time		0.0		0.0		0.0		0.0		ns
tFSU	Global clock setup time of fast input		2.5		2.5		3.0		3.0		ns
tFH	Global clock hold time of fast input		0.0		0.0		0.5		0.5		ns
tCO1	Global clock to output delay	C1 = 35 pF		3.2		4.0		4.5		5.0	ns
tCH	Global clock high time		2.0		2.5		3.0		4.0		ns
tCL	Global clock low time		2.0		2.5		3.0		4.0		ns
tASU	Array clock setup time		0.7		0.9		3.0		2.0		ns
tAH	Array clock hold time		1.8		2.1		2.0		3.0		ns

**Table 32. EPM7128S Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-15		
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.2		0.5		0.5		2.0	ns
$t_{IO}$	I/O input pad and buffer delay			0.2		0.5		0.5		2.0	ns
$t_{FIN}$	Fast input delay			2.6		1.0		1.0		2.0	ns
$t_{SEXP}$	Shared expander delay			3.7		4.0		5.0		8.0	ns
$t_{PEXP}$	Parallel expander delay			1.1		0.8		0.8		1.0	ns
$t_{LAD}$	Logic array delay			3.0		3.0		5.0		6.0	ns
$t_{LAC}$	Logic control array delay			3.0		3.0		5.0		6.0	ns
$t_{IOE}$	Internal output enable delay			0.7		2.0		2.0		3.0	ns
$t_{OD1}$	Output buffer and pad delay	C1 = 35 pF		0.4		2.0		1.5		4.0	ns
$t_{OD2}$	Output buffer and pad delay	C1 = 35 pF (6)		0.9		2.5		2.0		5.0	ns
$t_{OD3}$	Output buffer and pad delay	C1 = 35 pF		5.4		7.0		5.5		8.0	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		4.0		5.0		6.0	ns
$t_{ZX2}$	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		5.5		7.0	ns
$t_{ZX3}$	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		6.0	ns
$t_{SU}$	Register setup time		1.0		3.0		2.0		4.0		ns
$t_H$	Register hold time		1.7		2.0		5.0		4.0		ns
$t_{FSU}$	Register setup time of fast input		1.9		3.0		3.0		2.0		ns
$t_{FH}$	Register hold time of fast input		0.6		0.5		0.5		1.0		ns
$t_{RD}$	Register delay			1.4		1.0		2.0		1.0	ns
$t_{COMB}$	Combinatorial delay			1.0		1.0		2.0		1.0	ns
$t_{IC}$	Array clock delay			3.1		3.0		5.0		6.0	ns
$t_{EN}$	Register enable time			3.0		3.0		5.0		6.0	ns
$t_{GLOB}$	Global control delay			2.0		1.0		1.0		1.0	ns
$t_{PRE}$	Register preset time			2.4		2.0		3.0		4.0	ns
$t_{CLR}$	Register clear time			2.4		2.0		3.0		4.0	ns
$t_{PIA}$	PIA delay	(7)		1.4		1.0		1.0		2.0	ns
$t_{LPA}$	Low-power adder	(8)		11.0		10.0		11.0		13.0	ns

**Table 34. EPM7160S Internal Timing Parameters (Part 2 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-15		
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{CLR}$	Register clear time			2.4		3.0		3.0		4.0	ns
$t_{PIA}$	PIA delay	(7)		1.6		2.0		1.0		2.0	ns
$t_{LPA}$	Low-power adder	(8)		11.0		10.0		11.0		13.0	ns

**Notes to tables:**

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The  $t_{LPA}$  parameter must be added to this minimum width if the clear or reset signal incorporates the  $t_{LAD}$  parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3\text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in the low-power mode.

Tables 35 and 36 show the EPM7192S AC operating conditions.

**Table 35. EPM7192S External Timing Parameters (Part 1 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-15		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		7.5		10.0		15.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		7.5		10.0		15.0	ns
t <sub>SU</sub>	Global clock setup time		4.1		7.0		11.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		3.0		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.5		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		4.7		5.0		8.0	ns
t <sub>CH</sub>	Global clock high time		3.0		4.0		5.0		ns
t <sub>CL</sub>	Global clock low time		3.0		4.0		5.0		ns
t <sub>ASU</sub>	Array clock setup time		1.0		2.0		4.0		ns

**Table 38. EPM7256S Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-15		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.3		0.5		2.0	ns
$t_{IO}$	I/O input pad and buffer delay			0.3		0.5		2.0	ns
$t_{FIN}$	Fast input delay			3.4		1.0		2.0	ns
$t_{SEXP}$	Shared expander delay			3.9		5.0		8.0	ns
$t_{PEXP}$	Parallel expander delay			1.1		0.8		1.0	ns
$t_{LAD}$	Logic array delay			2.6		5.0		6.0	ns
$t_{LAC}$	Logic control array delay			2.6		5.0		6.0	ns
$t_{IOE}$	Internal output enable delay			0.8		2.0		3.0	ns
$t_{OD1}$	Output buffer and pad delay	C1 = 35 pF		0.5		1.5		4.0	ns
$t_{OD2}$	Output buffer and pad delay	C1 = 35 pF (6)		1.0		2.0		5.0	ns
$t_{OD3}$	Output buffer and pad delay	C1 = 35 pF		5.5		5.5		8.0	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		5.0		6.0	ns
$t_{ZX2}$	Output buffer enable delay	C1 = 35 pF (6)		4.5		5.5		7.0	ns
$t_{ZX3}$	Output buffer enable delay	C1 = 35 pF		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		5.0		6.0	ns
$t_{SU}$	Register setup time		1.1		2.0		4.0		ns
$t_H$	Register hold time		1.6		3.0		4.0		ns
$t_{FSU}$	Register setup time of fast input		2.4		3.0		2.0		ns
$t_{FH}$	Register hold time of fast input		0.6		0.5		1.0		ns
$t_{RD}$	Register delay			1.1		2.0		1.0	ns
$t_{COMB}$	Combinatorial delay			1.1		2.0		1.0	ns
$t_{IC}$	Array clock delay			2.9		5.0		6.0	ns
$t_{EN}$	Register enable time			2.6		5.0		6.0	ns
$t_{GLOB}$	Global control delay			2.8		1.0		1.0	ns
$t_{PRE}$	Register preset time			2.7		3.0		4.0	ns
$t_{CLR}$	Register clear time			2.7		3.0		4.0	ns
$t_{PIA}$	PIA delay	(7)		3.0		1.0		2.0	ns
$t_{LPA}$	Low-power adder	(8)		10.0		11.0		13.0	ns

**Notes to tables:**

- (1) These values are specified under the recommended operating conditions shown in [Table 14](#). See [Figure 13](#) for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The  $t_{LPA}$  parameter must be added to this minimum width if the clear or reset signal incorporates the  $t_{LAD}$  parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3 \text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPTW}$  parameters for macrocells running in the low-power mode.

## Power Consumption

Supply power (P) versus frequency ( $f_{MAX}$  in MHz) for MAX 7000 devices is calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The  $P_{IO}$  value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in [Application Note 74 \(Evaluating Power for Altera Devices\)](#).

The  $I_{CCINT}$  value, which depends on the switching frequency and the application logic, is calculated with the following equation:

$$I_{CCINT} =$$

$$A \times MC_{TON} + B \times (MC_{DEV} - MC_{TON}) + C \times MC_{USED} \times f_{MAX} \times \text{tog}_{LC}$$

The parameters in this equation are shown below:

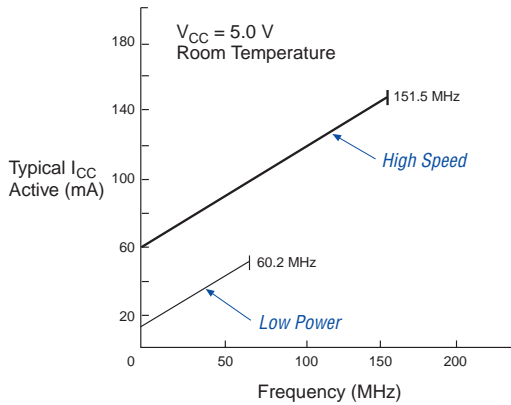
$MC_{TON}$	=	Number of macrocells with the Turbo Bit option turned on, as reported in the MAX+PLUS II Report File (.rpt)
$MC_{DEV}$	=	Number of macrocells in the device
$MC_{USED}$	=	Total number of macrocells in the design, as reported in the MAX+PLUS II Report File (.rpt)
$f_{MAX}$	=	Highest clock frequency to the device
$\text{tog}_{LC}$	=	Average ratio of logic cells toggling at each clock (typically 0.125)
A, B, C	=	Constants, shown in <a href="#">Table 39</a>



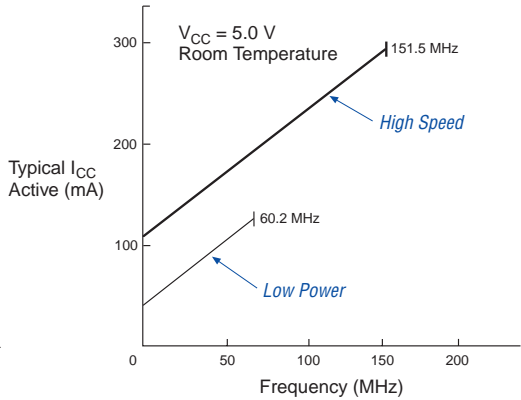
Figure 14 shows typical supply current versus frequency for MAX 7000 devices.

Figure 14.  $I_{CC}$  vs. Frequency for MAX 7000 Devices (Part 1 of 2)

EPM7032



EPM7064



EPM7096

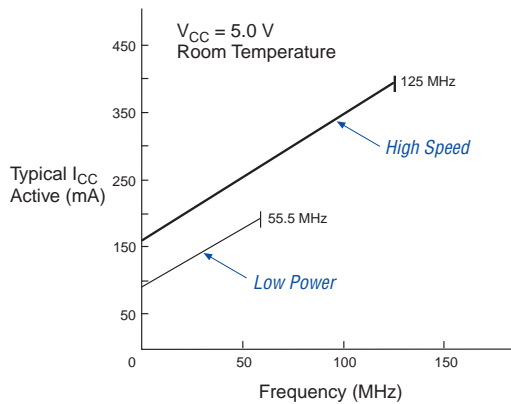


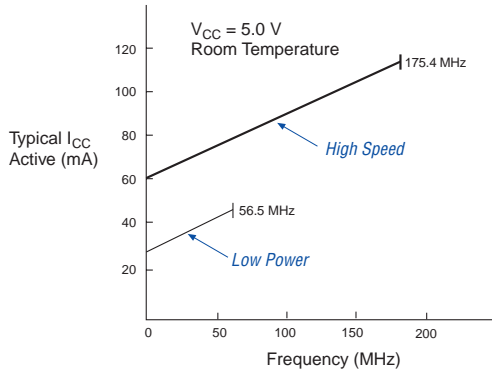
Figure 15 shows typical supply current versus frequency for MAX 7000S devices.

**Figure 15.  $I_{CC}$  vs. Frequency for MAX 7000S Devices (Part 1 of 2)**

**EPM7032S**



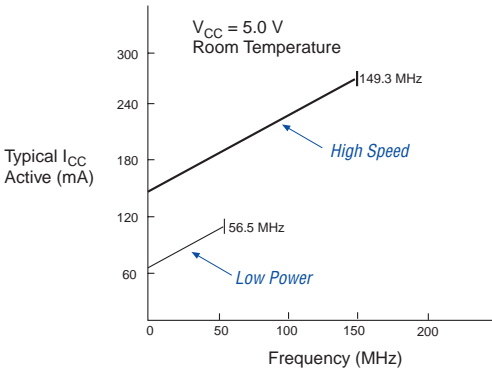
**EPM7064S**

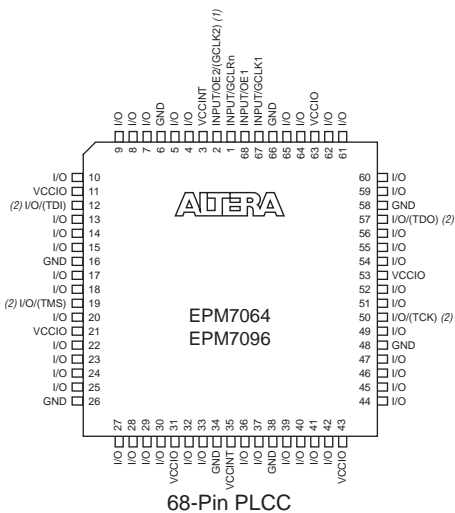


**EPM7128S**



**EPM7160S**

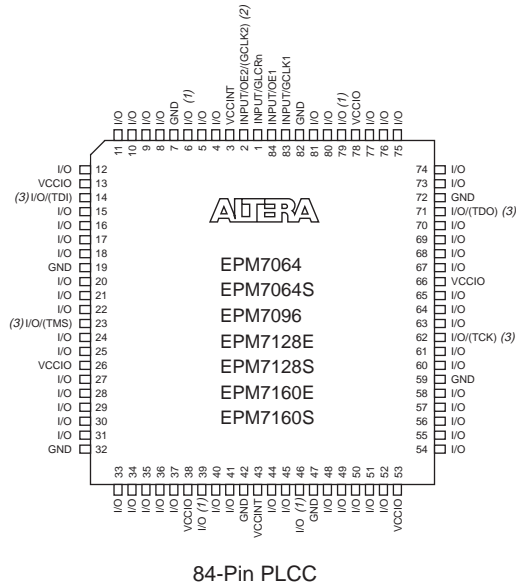


**Figure 17. 68-Pin Package Pin-Out Diagram***Package outlines not drawn to scale.***Notes:**

- (1) The pin functions shown in parenthesis are only available in MAX 7000E and MAX 7000S devices.
- (2) JTAG ports are available in MAX 7000S devices only.

**Figure 18. 84-Pin Package Pin-Out Diagram**

Package outline not drawn to scale.

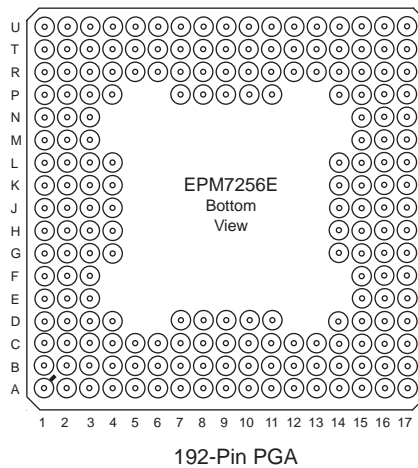


**Notes:**

- (1) Pins 6, 39, 46, and 79 are no-connect (N.C.) pins on EPM7096, EPM7160E, and EPM7160S devices.
- (2) The pin functions shown in parenthesis are only available in MAX 7000E and MAX 7000S devices.
- (3) JTAG ports are available in MAX 7000S devices only.

**Figure 21. 192-Pin Package Pin-Out Diagram**

Package outline not drawn to scale.

**Figure 22. 208-Pin Package Pin-Out Diagram**

Package outline not drawn to scale.

